

#### ROHS SCREENING ANALYSIS REPORT

NUMBER : TWNC00102798

APPLICANT: CACTUS TECHNOLOGIES LTD DATE : JAN 08, 2009 SUITE C 15/F CAPITAL TRADE CENTER 62 TSUN YIP STREET KWUN TONG KOWLOON HONG KONG

SAMPLE DESCRIPTION:	
ONE (1) GROUP OF SUBMITTED	
SAMPLE DESCRIPTION	PC CARD
	(1) PRINTED PLASTIC STICKER
	(2) SILVERY METAL COVER
	(3) TRANSPARENT PLASTIC FILM
	(4) BLACK PLASTIC FRAME
	(5) CONNECTOR - BLACK PLASTIC SOCKET
	(6) CONNECTOR - COPPERY METAL PIN
	(7) PCBA (CONNECTOR WAS EXCLUDED)
STYLE / ITEM NO.	KPXXXYZ(I)(XXX CAN BE 0~9 OR BLANK TO INDICATE
	THE DIFFERENT CAPACITY OF PC CARDS, y CAN BE M OR
	G TO INDICATE THE UNIT OF CAPACITY
	M :MEGABYTE, G :GIGABYTE, Z CAN BE R OR F TO
	INDICATE THÉ CARD TYPE ÀS REMOVABLE OR FIXED)
SERIES NO.	: -303
COUNTRY OF ORIGIN	: R.O.C.
DATE SAMPLE RECEIVED	: DEC 30, 2008
DATE TEST STARTED	: DEC 31, 2008
******************************	* * * * * * * * * * * * * * * * * * * *

TEST CONDUCTED:

AS REQUESTED BY THE APPLICANT, FOR DETAILS PLEASE REFER TO ATTACHED PAGES.

CONCLUSION:

TESTED SAMPLESSTANDARDRESULTSCREENING COMPONENTS OF<br/>SUBMITTED SAMPLESWITH REFERENCE TO TEST METHOD OF<br/>IEC 62321 - 111/54/CDV CHAPTER 6,<br/>SCREENING BY XRF SPECTROSCOPY AND<br/>CHEMICAL CONFIRMATION TEST FOR<br/>ROHS DIRECTIVE (2002/95/EC)RESULT<br/>PASS

#### REMARK:

AS REQUESTED BY THE APPLICANT, ONLY COMPONENTS SHOWN IN THIS REPORT WERE SCREENED BY XRF SPECTROSCOPY FOR 2002/95/EC. OTHER COMPONENTS WERE NOT SCREENED IN THIS REPORT.

CHEMICAL CONFIRMATION TESTS WERE CONDUCTED TO VERIFY THE INCONCLUSIVE RESULTS OF XRF TESTS.

AUTHORIZED BY: ON BEHALF OF INTERTEK TESTING SERVICES TAIWAN LIMITED



K. Y. LIANG DIRECTOR THIS REPORT SHALL NOT BE REPRODUCED EXCEPT IN FULL, WITHOUT THE WRITTEN APPROVAL OF THE LABORATORY.



#### TEST CONDUCTED

THE ROHS SCREENING ANALYSIS IS PERFORMED BY AN ED-XRF (ENERGY DISPERSIVE X-RAY FLUORESCENCE) ANALYZER. THE ANALYZER DETERMINES THE CHEMISTRY OF A SCREENED COMPONENT BY MEASURING THE SPECTRUM OF CHARACTERISTIC X-RAY EMITTED BY DIFFERENT ELEMENTS IN THE SAMPLE, WHICH SUBJECTED TO X-RAY RADIATION. IN THE WAY THE ANALYZER IS ABLE TO DETERMINE WHICH ELEMENT IN THE PERIODIC SYSTEM THAT IS PRESENT IN SCREENED COMPONENTS.

DETERMINATION OF TOTAL VALUE OF REGULATED SUBSTANCES IN ELECTROTECHNICAL PRODUCTS, ELEMENTS OF CADMIUM (Cd), LEAD (Pb), MERCURY (Hg), CHROMIUM (Cr) AND BROMINE (Br) CONTENT WERE MEASURED BY XRF SPECTROSCOPY FOR ROHS RESTRICTED SUBSTANCES. THE ANALYZER IS THEREFORE UNABLE TO DETERMINE IF IT IS PBB, PBDE, Cr(VI) OR NON RESTRICTED BROMINE AND CHROMIUM SUBSTANCES IN THE SAMPLE.

CORRENTED	XRF RESULT			CHEMICAL
SCREENED COMPONENT	ELEMENT	SCREENED RESULT (ppm)	CONCLUSION	CONFIRMATION RESULT (ppm)
	Cd	ND	PASS	
	Pb	ND	PASS	
(1)	Hg	ND	PASS	NOT TESTED
	Cr	ND	PASS	
	Br	ND	PASS	
	Cd	ND	PASS	
	Pb	ND	PASS	
(2)	Hg	ND	PASS	Cr <sup>6+</sup> : NEGATIV
	Cr	195766	INCONCLUSIVE	
	Br	NA	NA	
	Cd	ND	PASS	
	Pb	ND	PASS	
(3)	Hg	ND	PASS	NOT TESTED
	Cr	ND	PASS	
	Br	ND	PASS	
(4)	Cd	ND	PASS	
	Pb	ND	PASS	
	Hg	ND	PASS	NOT TESTED
	Cr	ND	PASS	
	Br	ND	PASS	

(I) TEST RESULT SUMMARY:



### TEST CONDUCTED

(I) TEST RESULT SUMMARY:

GODEENED	SCREENED XRF RESULT			CHEMICAL
COMPONENT	ELEMENT	SCREENED RESULT (ppm)	CONCLUSION	CONFIRMATION RESULT (ppm)
	Cd	ND	PASS	
	Pb	ND	PASS	
(5)	Hg	ND	PASS	NOT TESTED
	Cr	ND	PASS	
	Br	ND	PASS	
	Cd	ND	PASS	
	Pb	ND	PASS	
(6)	Hg	ND	PASS	NOT TESTED
	Cr	ND	PASS	
Br		NA	NA	
	Cd			Cd: ND
(7)(#)	Pb			Pb: 16
	Hg			Hg: ND
	Cr			Cr <sup>6+</sup> : ND
	Br			PBBs: ND PBDEs: ND

REMARKS: ppm = PARTS PER MILLION = mg/kg = NOT DETECTED AND PASS, THE SCREENED SAMPLE IS FOUND ND TO BE UNDER DETECTION LIMIT OF TABLE  ${\rm I\hspace{-.1em}I}$  . INCONCLUSIVE = THE SCREENED COMPONENT MAY HAVE POTENTIAL NON-COMPLIANCE AND CONFIRMATION TESTING BY WET CHEMICAL ANALYSIS MAY BE DESIRED TO OBTAIN A QUANTITATIVE RESULT. PASS = THE SCREENED COMPOENT IS FOUND TO BE PASS AND BELOW THE LOWER SCREENING THRESHOLD LIMIT OF TABLE  $I\!I$  . NA = NOT APPLICABLE = SAMPLES WERE GROUND AND RANDOMLY SELECTED FOR TEST # NEGATIVE = A NEGATIVE TEST RESULT INDICATES NO PRESENCE OF Cr(VI), LESS THAN THRESHOLD OF 1 mg/kg FOR SPOT TEST PROCEDURES. 



# TEST CONDUCTED

(  $\rm II$  ) XRF SCREENING LIMITS IN mg/kg FOR REGULATED ELEMENTS IN VARIOUS MATRIES.

ELEMENT	POLYMER MATERIALS	METALLIC MATERIALS	COMPOSITE MATERIALS
Cd	$P \leq 70 < X < 130 \leq F$	$P \leq 70 < X < 130 \leq F$	$P \leq 70 < X < 150 \leq F$
Pb	$P \leq 700 < X < 1300 \leq F$	$P \leq 700 < X < 1300 \leq F$	$P \le 500 < X < 1500 \le F$
Hg	$P \le 700 < X < 1300 \le F$	$P \le 700 < X < 1300 \le F$	$P \le 500 < X < 1500 \le F$
Cr	P ≤ 700 < X	P ≤ 700 < X	P ≤ 500 < X
Br	P ≤ 300 < X	NOT APPLICABLE	P ≤ 250 < X

P = PASS

X = INCONCLUSIVE RESULT

F = FAIL

mg/kg = MILLIGRAM PER KILOGRAM = ppm

(Ⅲ) ESTIMATED DETECTION LIMITS IN mg/kg FOR REGULATED ELEMENTS IN VARIOUS MATRICES.

ELEMENT	POLYMER MATERIALS	METALLIC MATERIALS	COMPOSITE MATERIALS
Cd	50	70	70
Pb	100	200	200
Hg	100	200	200
Cr	100	200	200
Br	200	NOT APPLICABLE	200
*****			



# TEST CONDUCTED

(IV) TEST METHOD

TESTING ITEM	TESTING METHOD	REPORTING LIMIT
CADMIUM (Cd) CONTENT	WITH REFERENCE TO IEC 62321-111/54/CDV IN CLAUES 11/12/13, BY MICROWAVE DIGESTION UNTIL THE TESTED SAMPLES ARE TOTALLY DISSOLVED AND DETERMINED BY ICP-OES	2 ppm
LEAD (Pb) CONTENT	WITH REFERENCE TO IEC 62321-111/54/CDV IN CLAUES 11/12/13, BY MICROWAVE DIGESTION UNTIL THE TESTED SAMPLES ARE TOTALLY DISSOLVED AND DETERMINED BY ICP-OES	2 ppm
MERCURY (Hg) CONTENT	WITH REFERENCE TO IEC 62321-111/54/CDV IN CLAUES 10, BY MICROWAVE DIGESTION UNTIL THE TESTED SAMPLES ARE TOTALLY DISSOLVED AND DETERMINED BY ICP-OES	2 ppm
CHROMIUM VI (Cr <sup>6+</sup> ) CONTENT (FOR MATERIAL OTHER THAN METAL)	WITH REFERENCE TO IEC 62321-111/54/CDV IN CLAUES 9, BY ALKALINE DIGESTION AND DETERMINED BY UV-VIS SPECTROPHOTOMETER	l ppm
CHROMIUM VI (Cr <sup>6+</sup> ) CONTENT (QUALITATIVE METHOD FOR METAL)	WITH REFERENCE TO IEC 62321-111/54/CDV IN CLAUES 8, BY SPOT TEST	NEGATIVE (< 1 mg/kg)
WITH REFERENCE TO IEC 62321-111/54/CDV POLYBROMINATED IN CLAUES 7, BY SOLVENT EXTRACTION AND DETERMINED BY GC-MSD AND FURTHER HPLC CONFIRMATION WHEN NECESSARY		5 ppm
POLYBROMINATED DIPHENYL ETHERS (PBDEs)	WITH REFERENCE TO IEC 62321-111/54/CDV IN ANNEX A, BY SOLVENT EXTRACTION AND DETERMINED BY GC-MSD AND FURTHER HPLC CONFIRMATION WHEN NECESSARY	5 ppm

REMARKS : REPORTING LIMIT = QUANTITATION LIMIT OF ANALYTE IN SAMPLE WITH REFERENCE TO 111/54/CDV VERSION 2006-05-05, THE METHOD IS STILL UNDER DEVELOPMENT BY IEC TC/111 WG3 AND IS ADOPTED ONLY UPON CLIENT'S REQUEST.



#### TEST CONDUCTED

# **DISCLAIMERS:**

THE NUMERICAL TEST DATA OF THIS XRF SCREENING REPORT IS FOR REFERNECE PURPOSES ONLY DUE TO THE DATA VARIATION INCURRED FROM VARIOUS FACTORS AS DESCRIBED IN NEXT PARAGRAPH. THE APPLICANT SHALL MAKE ITS/HIS/HER OWN JUDGEMENT AS TO WHETHER THE INFORMATION PROVIDED IN THIS XRF SCREENING REPORT IS SUFFICIENT FOR ITS/HIS/HER PURPOSES.

THE RESULTS SHOWN IN THIS XRF SCREENING REPORT WILL DIFFER BASED ON VARIOUS FACTORS, INCLUDING BUT NOT LIMITED TO, THE SAMPLE SIZE, THICKNESS, AREA, SURFACE FLATNESS, EQUIPMENT PARAMETERS AND MATRIX EFFECT (e.g. PLASTIC, RUBBER, METAL, GLASS, CERAMIC ETC.). FURTHER WET CHEMICAL PRE-TREATMENT WITH RELEVANT CHEMICAL EQUIPMENT ANALYSIS ARE REQUIRED TO OBTAIN QUANTITATIVE DATA.

#### (V) ROHS REQUIREMENT:

RESTRICTED SUBSTANCES	LIMITS
CADMIUM (Cd)	0.01% (100 ppm)
LEAD (Pb)	0.1% (1000 ppm)
MERCURY (Hg)	0.1% (1000 ppm)
CHROMIUM (VI) (Cr <sup>6+</sup> )	0.1% (1000 ppm)
POLYBROMINATED BIPHENYLS (PBBs)	0.1% (1000 ppm)
POLYBROMINATED DIPHENYL EHTERS (PBDEs)	0.1% (1000 ppm)

THE ABOVE LIMITS WERE QUOTED FROM 2002/95/EC AND AMENDMENT 2005/618/EC FOR HOMOGENEOUS MATERIAL.

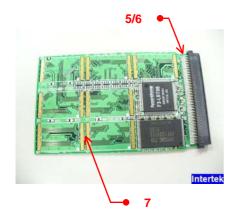
END OF REPORT



# TEST CONDUCTED



PHOTO



PAGE 7 OF 7